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| Notice of References Cited | Application/Control No. 10/812,412 | Applicant(s)/Patent Under Reexamination WANG ET AL. | |
| | Examiner Nathan W. Ha | Art Unit 2814 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------|----------------|
| | A | US-2004/0063277 A1 | 04-2004 | Chudzik et al. | 438/243 |
| | B | US-2004/0147074 A1 | 07-2004 | Sell et al. | 438/243 |
| | C | US-2004/0188739 A1 | 09-2004 | Takenaka et al. | 257/301 |
| | D | US-6,777,303 B2 | 08-2004 | Schrems et al. | 438/386 |
| | E | US-6,211,006 B1 | 04-2001 | Tsai et al. | 438/246 |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
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| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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